

Building High Reliability into Microsemi Designs with Synplify FPGA Tools

Microsemi Space Forum 2015, Synopsys



Microsemi
SPACE FORUM

Agenda

- FPGA SEU mitigation industry trends and best practices
 - Market trends
 - What's needed and when
- Current solutions
 - Overview FPGA design tools
 - Hardware debug and operation visibility
 - DO-254 support
 - SEU mitigation circuitry creation and error monitors
- New best practices → What's next?
 - Local TMR best practices
 - Validating that TMR occurred and that it works
 - Error monitoring and access
 - Solutions for Microsemi RTG4



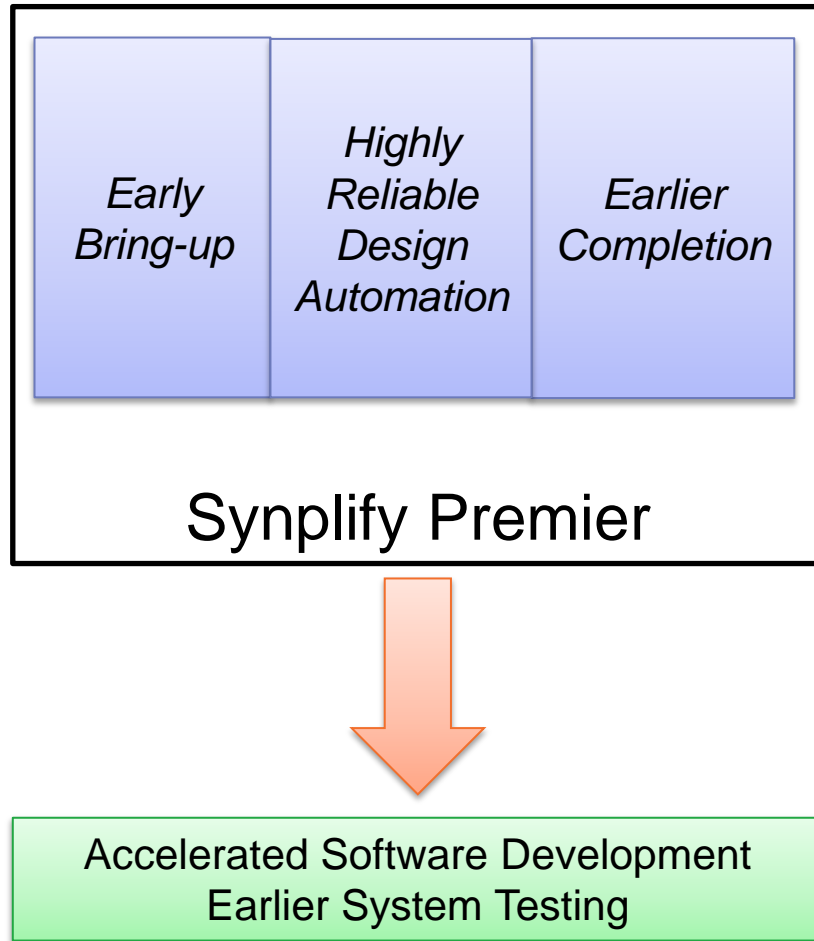
FPGA Military/Aerospace Solutions



- Mil/Aero market trends for FPGA systems
 - Need highest datapath performance in smallest area
 - High reliability and SEU error mitigation
 - Strict processes for circuit creation and verification
 - Reliable operation in harsh and high radiation environments
 - Support for multiple FPGA vendor suppliers
- Synplify FPGA solutions provide
 - DO-254 support and process compliance
 - Debug operating design in RTL
 - Automation of high reliability design techniques
 - Highest system performance in smallest area
 - Support for Verilog, VHDL, VHDL-2008 and System Verilog

Synplify enables high reliability, fast runtimes and deep debug

Synplify Premier offers 10x Faster Hardware Bring-up for Microsemi FPGAs



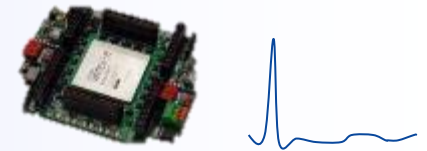
- Single-pass design debug
 - Upfront RTL and constraint checks
 - Finds all errors in a single compile
 - Diagnostic reporting
 - Fast synthesis (low QoR) mode
- Highly Reliable Automation
 - Hamming-3 error detection and correction design automation
- Quickly apply improvements
 - Hierarchical & incremental flows
 - Multi-machine synthesis

Why is There a High Reliability Problem?

Radiation-induced circuit glitches
(SEUs, SETs)



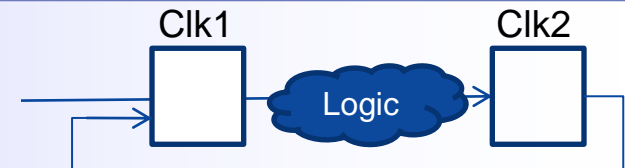
Power rail glitch



Power supply glitch or brown-out



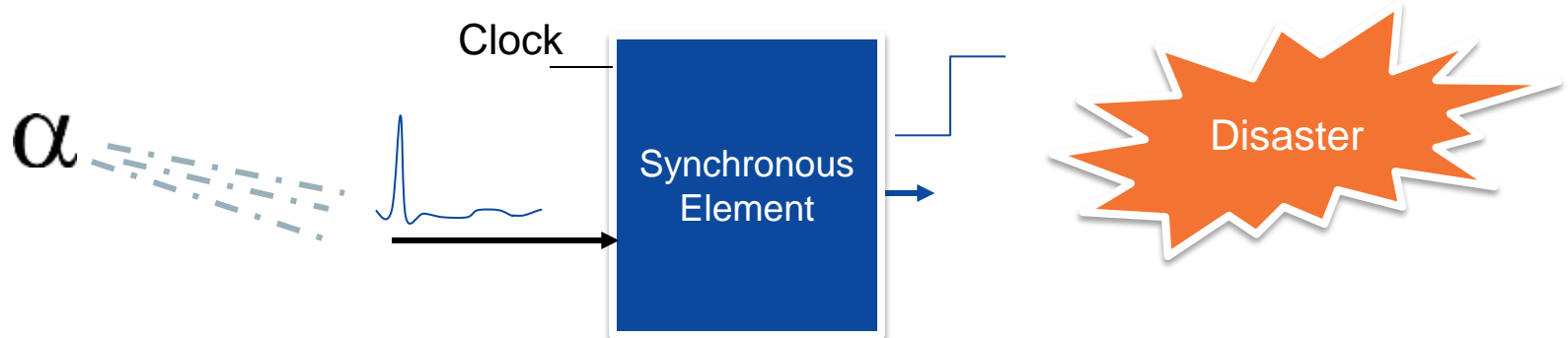
Meta-stability due to design flaws
(failure to synchronize the circuit)



SETs and SEUs

Glitches clocked into a synchronous element can cause operation errors and ultimately system failure

- Impacts memories, registers, state machines



SET (Single Event Transient)

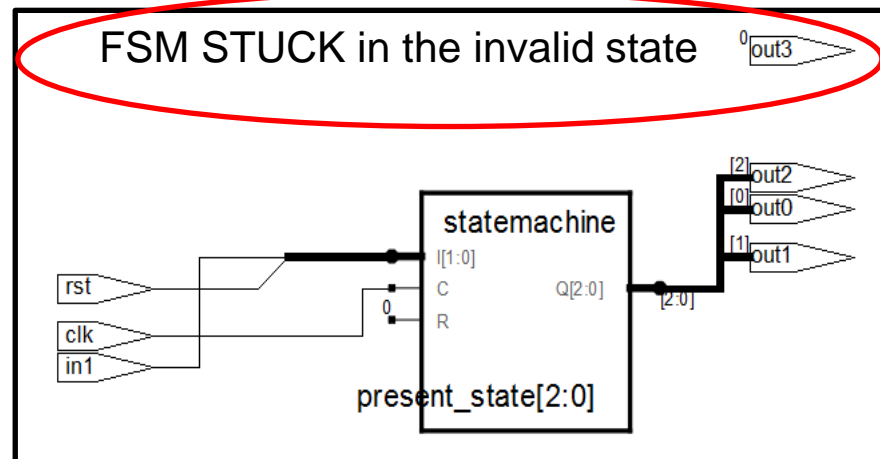
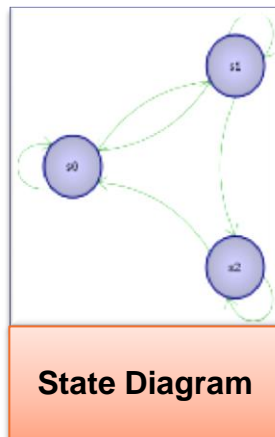
A current spike or “glitch” in a signal that occurs due to ionization or electromagnetic radiation

SEU (Single Event Upset)

Incorrect signal (SET) captured by a synchronous element that impacts its internal state and / or output

SEUs Cause Incorrect Behavior or FSM Failure

A flip in a register bit within an FSM can cause what was assumed to be an “unreachable” or “invalid” state to be reached



RTL others clause that would handle state transition behavior out of an unreachable state is optimized away by default by the synthesis tool

Synplify Premier Automates Design for High Reliability

- Monitor for Soft Errors "Bit flips"
- Restore Stable Operation

Control Logic
and FSMs



Safe FSMs
w/ Hamming-3

Local and
Distributed TMR

Memories



Preserve Critical
Circuitry

RAM TMR

ECC RAM
Inference

Duplicate w/
Compare Triggers
Scrubbing

User Logic,
I/O's



High Reliability
Reporting

Distributed TMR

I/O Replication
and Error
Monitoring

Duplicate with
Compare

*Not supported for
Microsemi

Radiation-Induced Error (SEU) Mitigation

Susceptibility to Particle Radiation Effects

Device Type	RAD-HARD	Anti-Fuse/ Flash	SRAM
Register	Low	Moderate	Low
Block RAM	Very High unless Error Detection & Correction used	Very High unless Error Detection & Correction used	Very High
Logic Cells	None	None	High
Routing Matrix	None	None	High

Current Solutions

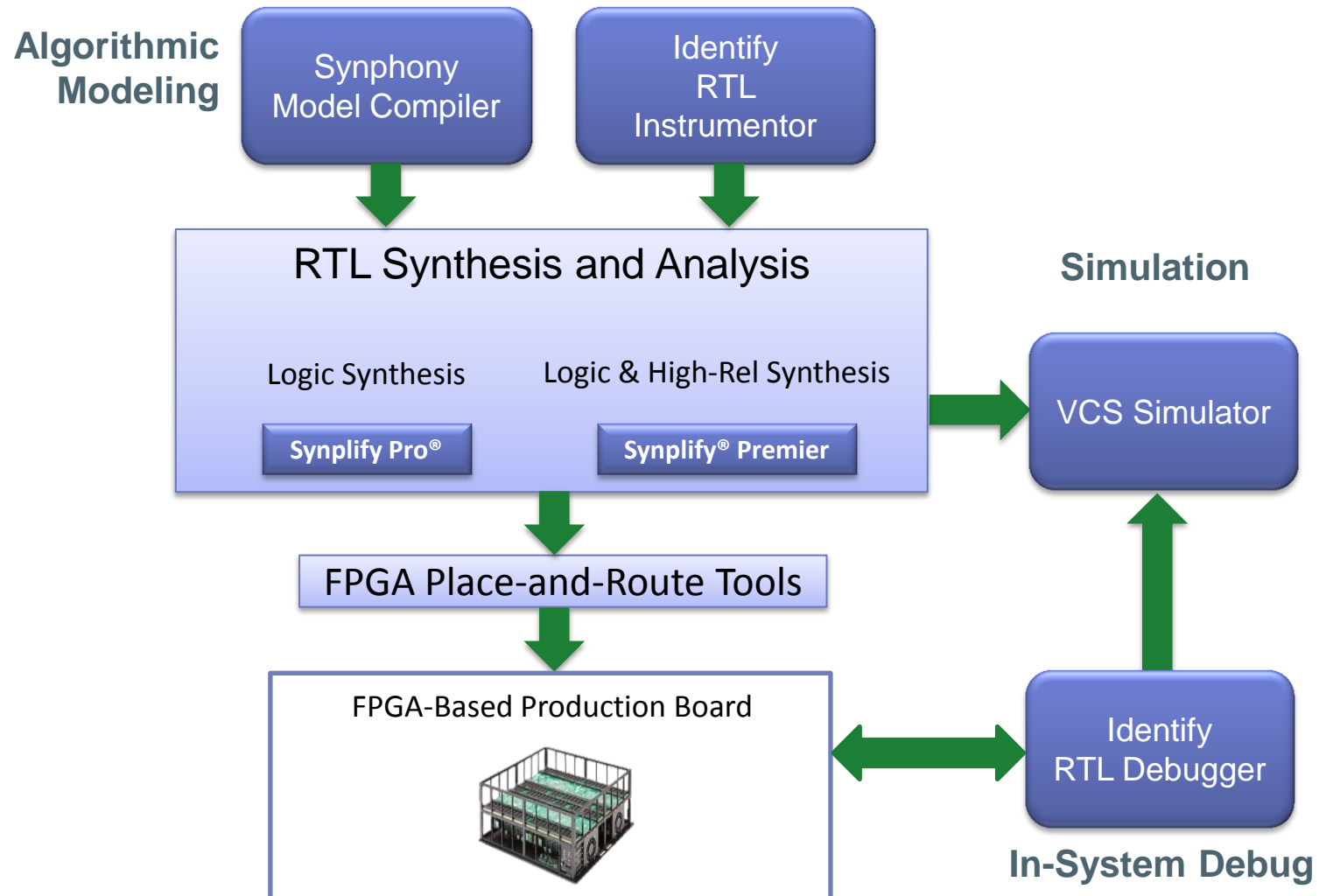
Overview FPGA design tools

Hardware debug and operation visibility

DO-254 support

SEU mitigation circuitry creation and error monitors

Synopsys FPGA Design Suite

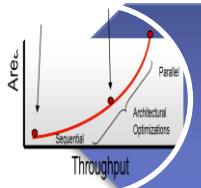


Synphony Model Compiler Overview

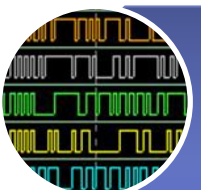
Save Months in Design/Verification of Signal Processing Systems



Signal Processing IP library



High-Level Design and Verification from Simulink/MATLAB



High-performance verification for RTL and C-model system simulation

Synphony Signal Processing IP Library



High-Level Design (Simulink/MATLAB)



Synphony Model Compiler High-Level Synthesis



Synplify for Microsemi



Verification

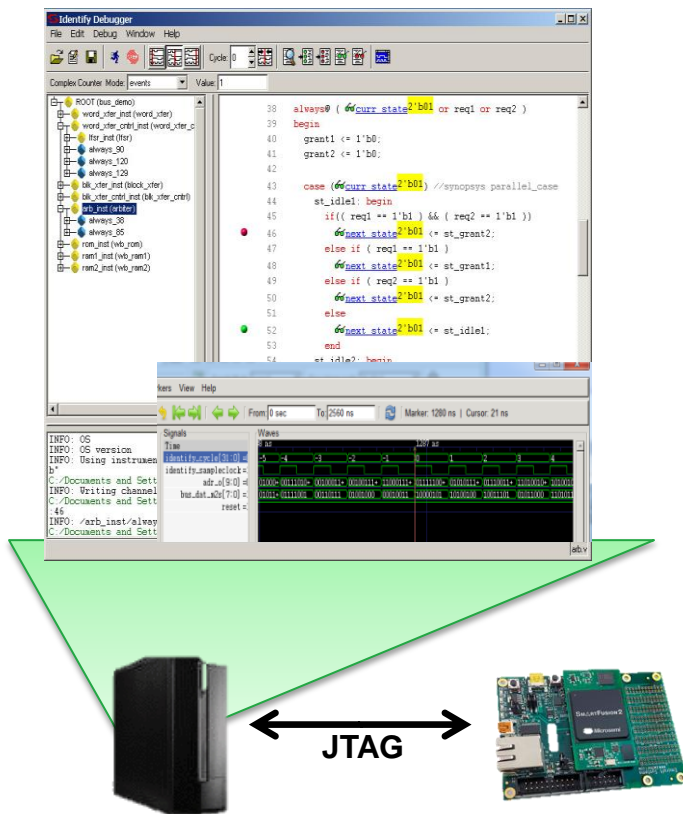
- Multi-device
- DSP Mapping
- Timing Closure

- RTL Testbench
- C-Models
- Prototypes

- Microsemi provides “Synphony Model Compiler” software distribution for Microsemi FPGA devices
- Synopsys enables Synphony Model Compiler product enabling all FPGA devices

Synplify Debug Provides Simulator-Like Visibility into FPGA Hardware Operation

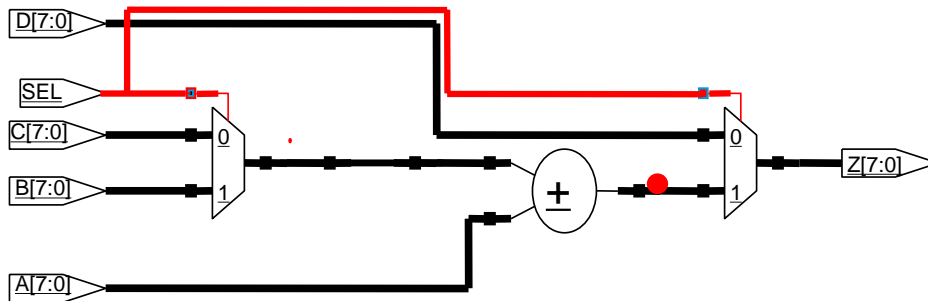
- Faster debug & higher design visibility
 - Traditional debug takes too long
 - Logic analyzers are insufficient
 - Debug at speed in system required
- Debug were you design
 - Instrument/debug directly in RTL
 - Quickly select signals for sampling/triggering
 - Capture signals at real-time speed
 - Powerful triggering for pinpointing a fault
 - Explore state spaces and conditions not easily reached by simulation
 - Integrated with Synplify Premier



- Microsemi provides “Identify” software distribution for Microsemi FPGA devices
- Synopsys enables Synplify Premier and Identify products enabling all FPGA devices

Identify Enables Requirements Traceability after Synthesis Optimizations

RTL representation

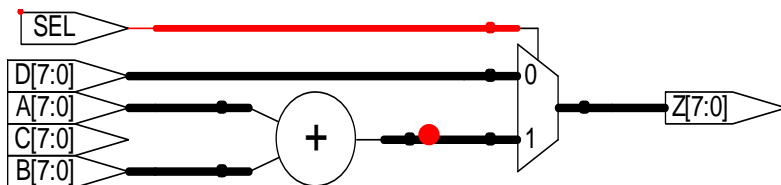


Synthesis

- *RTL Enumerated TYPES appear as 1's and 0's in netlist*
- *RAM, DSP inferencing and sequential optimization optimize node in RED away*



Optimized Gate Level Netlist



Synthesis performs optimizations

- Can cause debug node being absorbed or transformed
- No longer able to trace or probe these nodes
- Cannot relate their behavior in system back to your RTL

Instrument with Identify

- Nodes of interest preserved
- Relate behavior on board at nodes back to the RTL

Synplify Enables DO-254 Compliant Process

Traceability

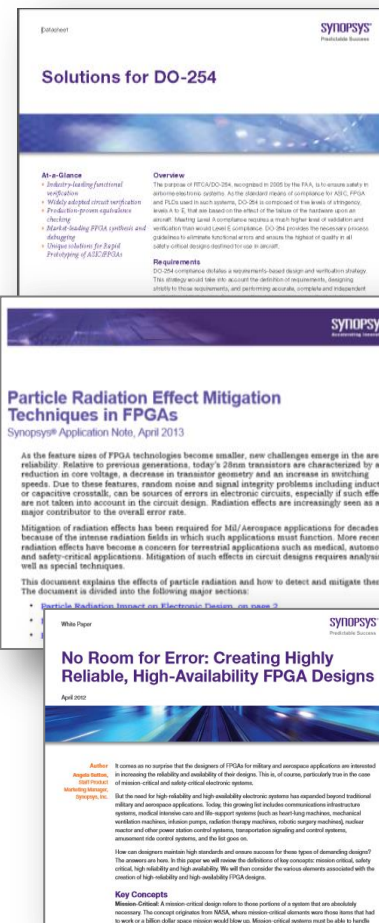
Schematics for Documentation
Timing Reports and Log files
Safe FSM and TMR Reports

Repeatability

Reproducible synthesis results
Lock down pre-verified blocks
Best Practices Safety-critical design

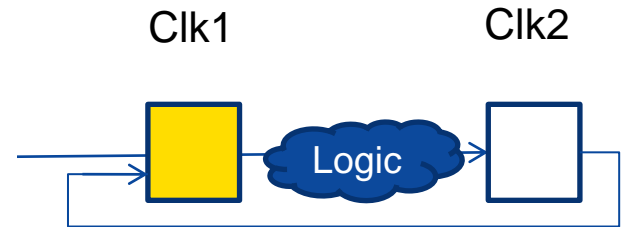
Equivalence

Simulator Integration
Node preservation control for equivalence
assurance & requirements trace



SEU Mitigation Practices – Synplify Pro & Premier

- Clock Domain Synchronization Assurance
 - Report alerts you to meta-stability problems due to design flaws such as failure to synchronize the circuit
- Preservation of Debug Circuitry and of Custom Error Detection and Mitigation Circuitry
 - Implementation during synthesis of RTL “others” clause that specifies your custom error mitigation circuitry
 - Attributes to designate “preserve during synthesis nodes needed for probing and debug, or for equivalence proving purposes”



```
always @ (in1,present_state)
case (present_state)
s0 : .....
s1 : .....
s2 : .....
s3 : ..... //no transition into S3
default : next_state <= s3;
endcase
```

Attributes
syn_keep syn_preserve
syn_hier syn_noprune
syn_probe

Single Event Upset Mitigation Practices

- Antifuse/flash device registers can be moderately susceptible to SEUs
- FSMs contain registers

Resource	Recommended solution	Synplify Version
Registers	Local TMR	Synplify Pro
FSMs	Hamming-3 Automatic Error Correction Specify how to return FSM from “unreachable state” to safe state by specifying and preserving the RTL “others” clause	Synplify Premier

TIP: *Be sure to instruct the synthesis software to preserve error-mitigation circuitry*

New Best Practices ... What's Next?

Local TMR Best Practices

Validating that TMR occurred and that it works

Error monitoring and access

Solutions for MicroSemi RTG4

New Industry Trends and Best Practices

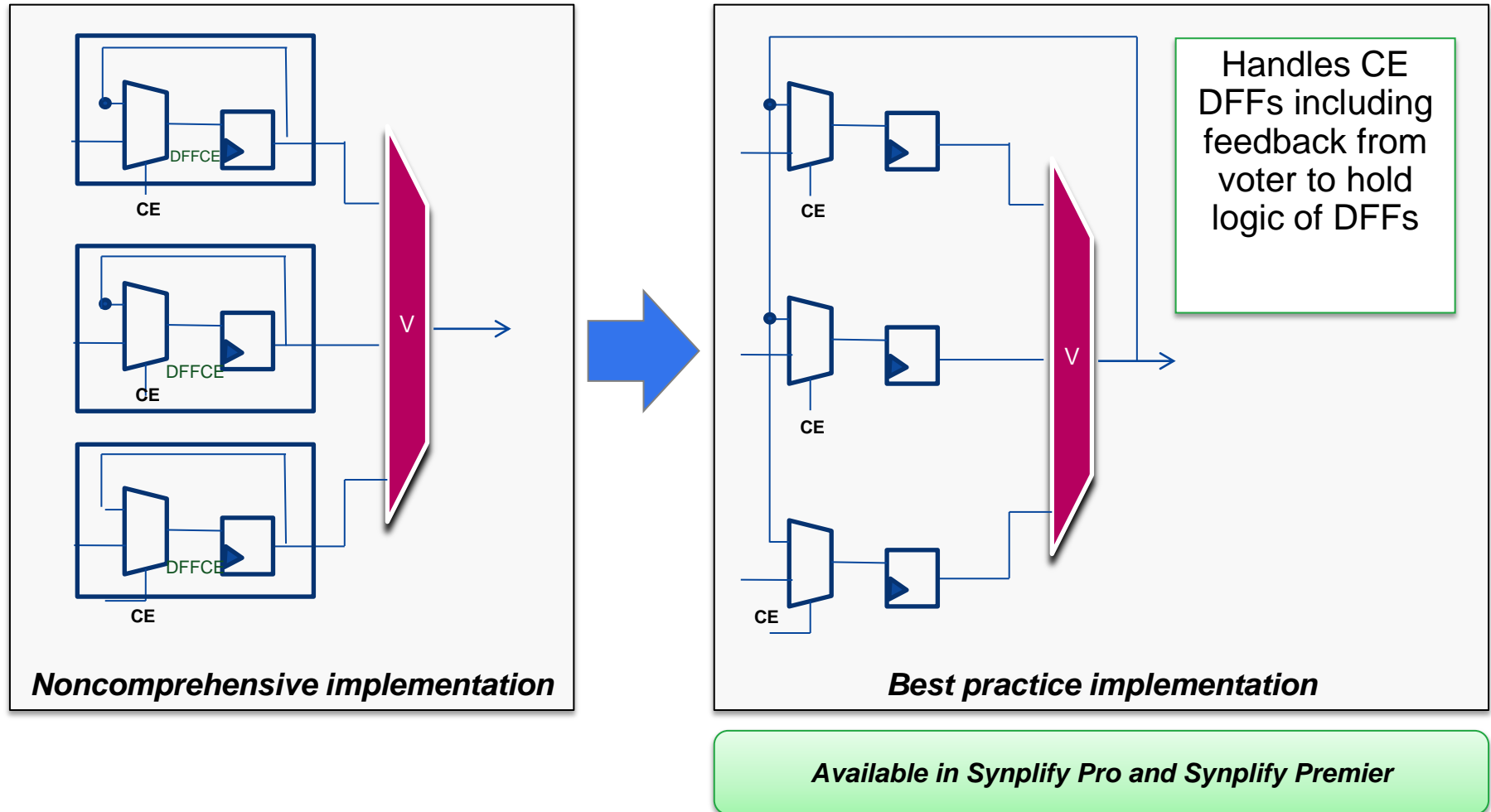
- TMR clock enable feedback loop in Local TMR & Distributed TMR circuitry
- Ways to determine “what best to TMR”
- Validation that TMR occurred
- Physical Separation of Triplicates



Synopsys is refining these solutions within Synplify Premier

Local TMR Best Practice

Enhances Local TMR implementation to include feedback from voter



Validating that TMR Occurred

distributed_tmr inst3.TMR_mod1_inst(TMR_mod1) IMPLEMENTED

1 High Reliability Report
2 -----

3 feature Instance(View) implementation-status External-Voterlogic Internal-Voterlogic error-monitored Comparator-count pipestage

4 -----

5 distributed_tmr inst3.TMR_mod2_inst.TMR_prob(TMR_mod3_TMR_prob_0) NOT IMPLEMENTED NA NA False NA NA

6 distributed_tmr inst3.TMR_mod1_inst.TMR_prob(TMR_mod3_TMR_prob) NOT IMPLEMENTED NA NA False NA NA

7 distributed_tmr inst3.TMR_mod2_inst(TMR_mod3) IMPLEMENTED 36 NA False NA NA

8 distributed_tmr inst3.TMR_mod1_inst(TMR_mod1) IMPLEMENTED 36 NA False NA NA

9 distributed_tmr TMR_loop_inst(TMR_loop) IMPLEMENTED 36 108 True 73 4

10 duplicate_with_compare DWC_inst(DWC) IMPLEMENTED NA NA True 37 2

11 -----

External-Voterlogic	Internal-Voterlogic	error-monitored	Comparator-count	pipestage
36	108	True	73	4

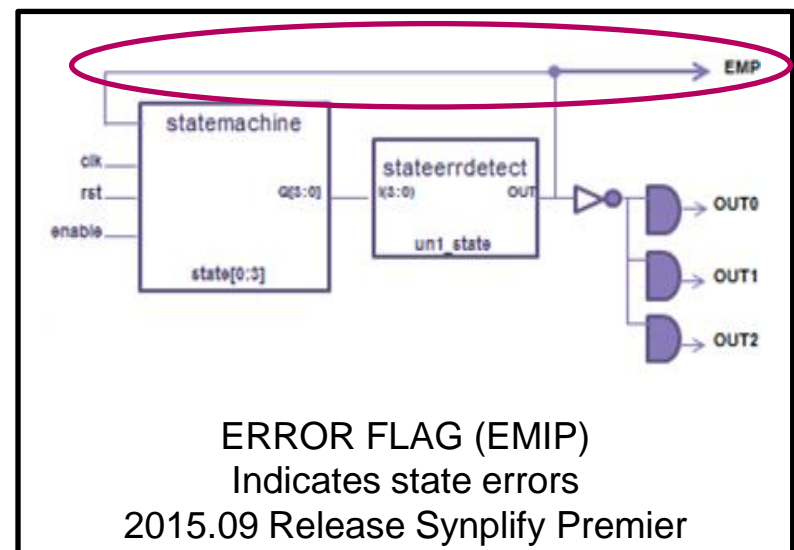
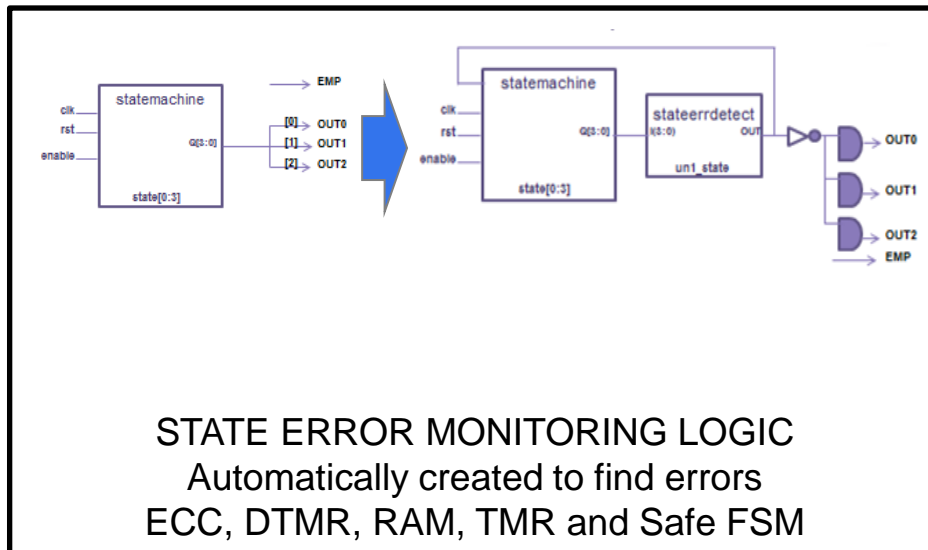
Synplify Premier reports and confirms where SEU mitigation circuitry implemented

- For Local TMR and Distributed TMR, Safe FSM
- Voter logic, sequential loops, error monitoring, comparator gates, pipestage resources

Error Monitoring & Access – FSM Example

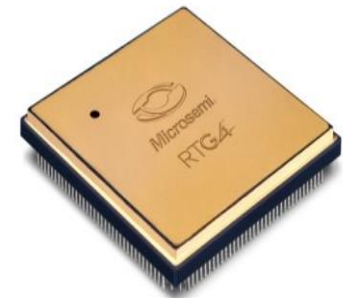
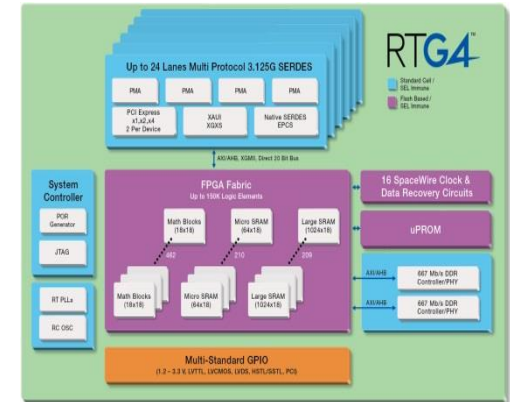
- Synthesis Attributes specify Error Nets to be monitored
- Synthesis creates error-monitoring logic and makes Error flag signal accessible
 - `set_option -safe_case 1`

```
syn_create_err_net {-name {error_flag} -inst {i:state[1:3]}}  
syn_connect -from {{n:error_flag} -to {t:EMIP.err_port}}
```



Synplify Premier MicroSemi RTG4 Solution

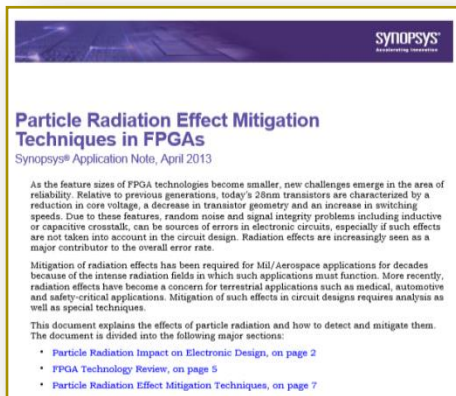
- Safe FSM
 - syn_encoding = safe
 - Using preserve & decode unreachable states logic
- Sequential logic and FSMs – Hamming 3 error detection and correction (EDAC)
- Support for Block RAMs
 - Inference of ECC block RAMs
 - Access to error bits similar to duplicate and compare.
- Local TMR for registers not required



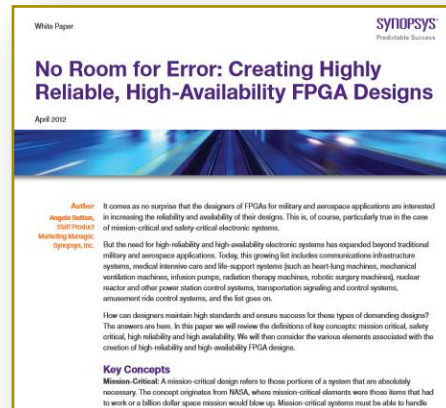
RTG4 design solution available in 2015.09 Synplify Premier release

More Information on Design for High Reliability

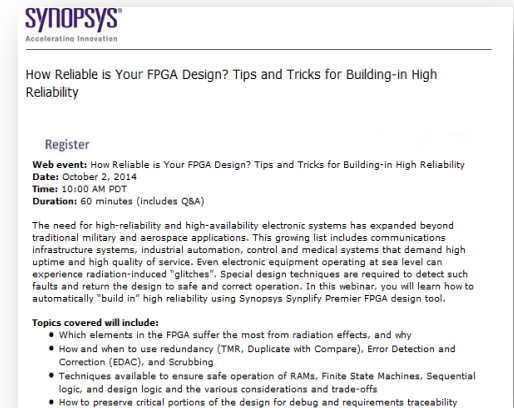
White Paper



App Note



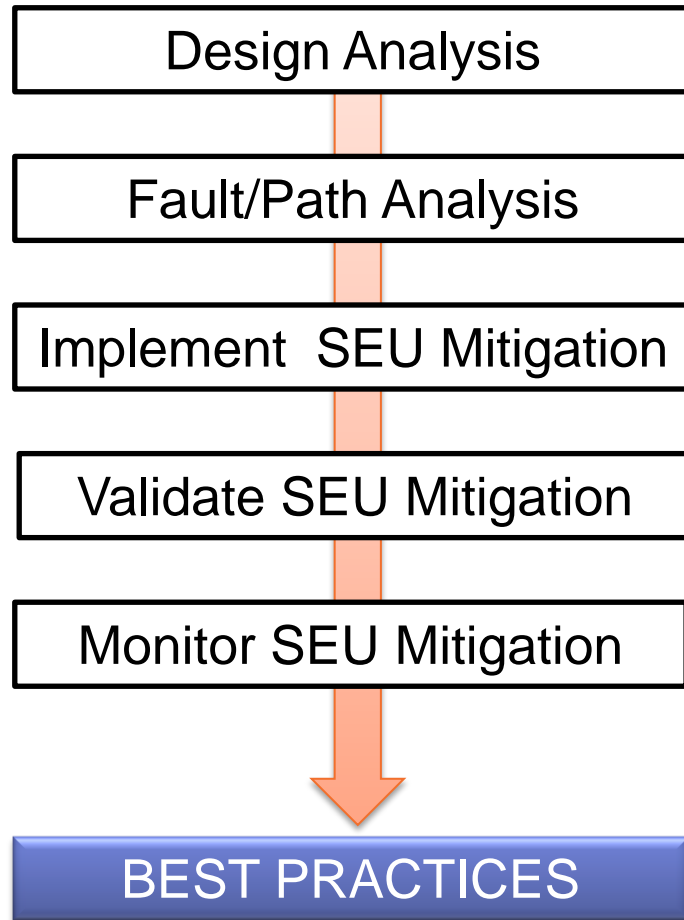
High Rel Webinar



<http://www.synopsys.com/fpga>

And visit us at our booth

Synplify Enables SEU Mitigation Methodologies



- Enhanced Local TMR and Distributed TMR for CE DFF
- TMR Reporting Trade-off Analysis and Control
- TMR and Safe FSM reporting and/or visualization
- Fault injection for Safe FSM and TMR (future technology)
- Ease of validation of error recovery
- Error Flag implementation



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Thank You



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